Microwave dielectric properties of CaB_2O_4-$CaSiO_3$ eutectic system for LTCC applications

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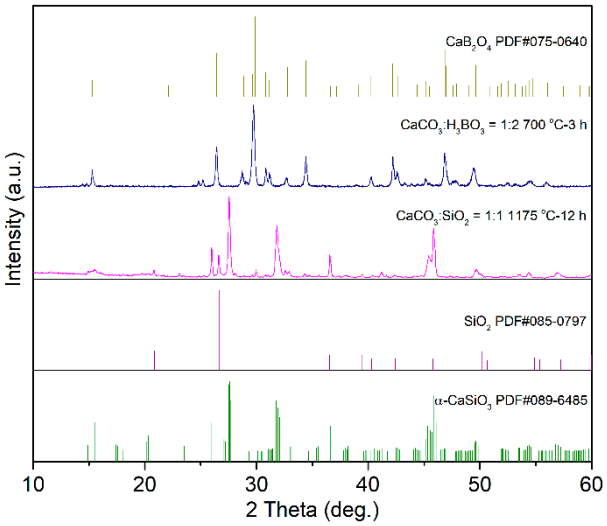


Figure S1 the XRD patterns of calcined at different temperature of CaB_2O_4 and $CaSiO_3$

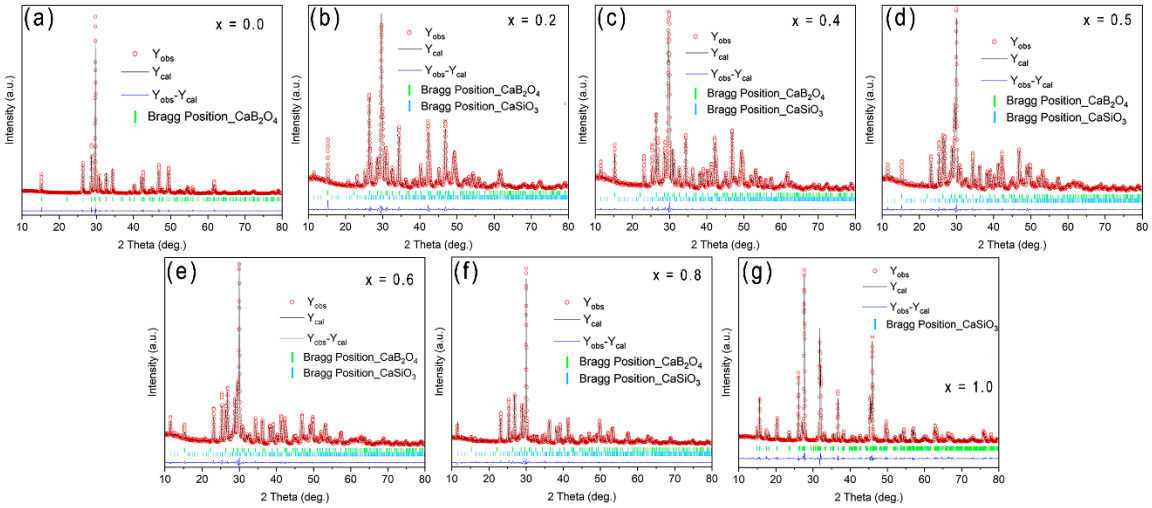


Figure S2 The Rietveld refinement results of (1-*x*)CaB_2O_4+*x*$CaSiO_3$

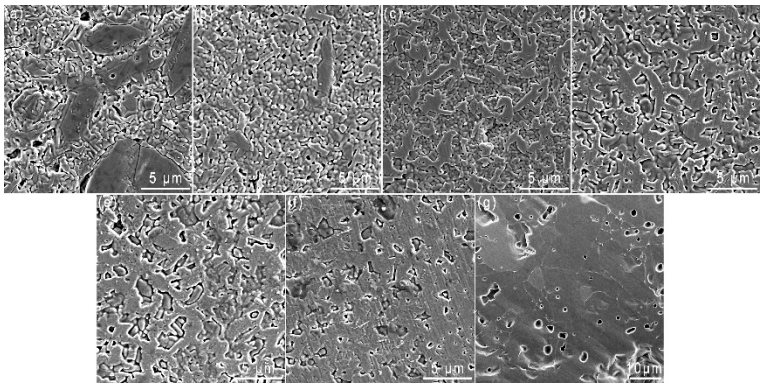


Figure S3 The microstructure of (1-x)CaB_2O_4+$x$$CaSiO_3$ ceramics sintered at their optimum temperature: (a) x = 0.1, (b) x = 0.2, (c) x = 0.4, (d) x = 0.5, (e) x = 0.6, (f) x = 0.8, (g) x = 1